ESD (HUMAN BODY MODE) TEST REPORT

Company ：**Fremont Micro Devices Co., LTD.**

Address ：**#5-8, 10-F, Changhong Science and Technology Building, Ke Ji Nan 12 Road, Nanshan District, Shenzhen, PRC**

Model Name ：**FT24C256A-UXX**

Date Received ：May 27, 2010

Date Tested ：May 27, 2010

TESTING LABORATORY IS ACCREDITED BY:

IEC/IECQ 17025 certificate of independent test laboratory approval

Certificate No.：T1117-1

ISO 9001 certificate is approved by TUV CERT certification body of TUV NORD Cert GmbH

WE HEREBY CERTIFY THAT:

The test(s) shown in the attachment were conducted according to the indicating procedures. We assume full responsibility for the accuracy and completeness of these tests and vouch for the qualifications of all personnel performing them.

	Name	Signature	Date
Testing Engineer	Jianbo Song	Jianbo Song	2010/5/27
Approving Manager	Alston Wang	Alston Wang	2010/5/27
Vice President	Coming Chen	Coming Chen	2010/5/27

Note：

1. This report will be invalid if reproduced in whole or in part.
2. This report refers only to the specimen(s) submitted to test, and is invalid if used separately.
3. This report is ONLY valid with the examination seal and signature of this institute.
4. The tested specimen(s) will only be preserved for thirty days from the date issued, if not collected by the applicant.

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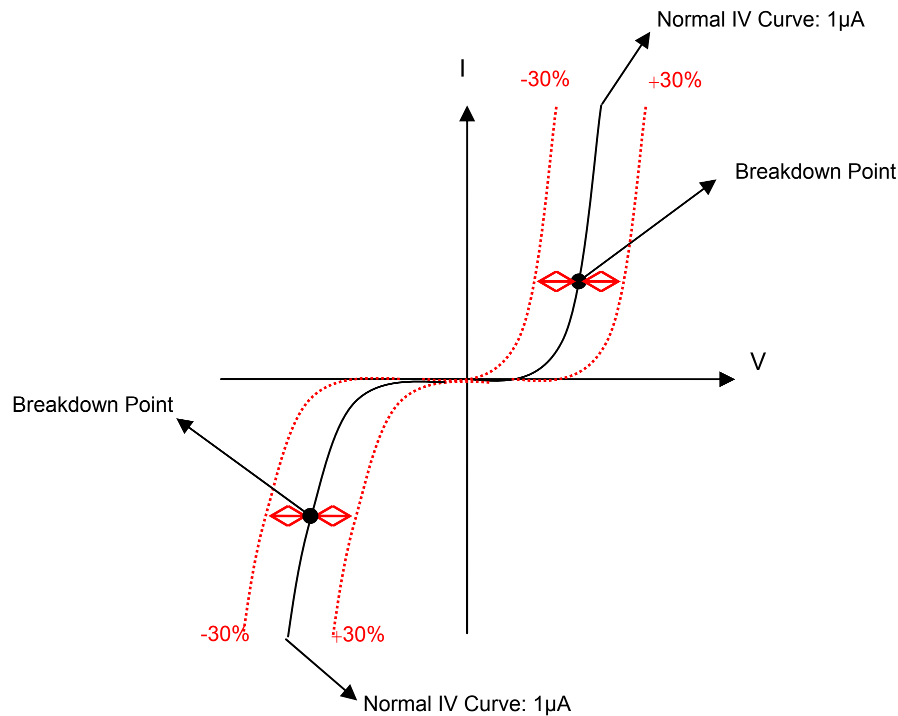
1. GENERAL INFORMATION

1.1 DESCRIPTION OF UNIT

MANUFACTURER	：Fremont Micro Devices Co., LTD.
DEVICE NAME	：FT24C256A-UXX
PACKAGED / PIN COUNT	：DIP8
REFERENCE DOCUMENT	：MIL-STD-883H Method 3015.8 Zap 3 pulse(s), Interval: 1.0 Sec.
TEST VOLTAGE	：500V ~ 2000V (±), Step: 500V (±)
SAMPLE QUANTITY	：18 pcs
FAILURE CRITERIA	：FOR V CHANGE AT 1μA ±30%

※ Failure Judgment: IV curve shift over 1μA±30% at breakdown point.



2. ESD (HUMAN BODY MODE) TEST

2.1 TEST EQUIPMENT

Test Equipment	Equipment S/N	Calibration Date:	Recommended Due Date:
KEYTEK ZAPMASTER 7/4	0008189	May 29, 2009	May 28, 2010

2.2 LABORATORY AMBIENCE CONDITION

Temperature：23±5°C
Relative humidity：55%±10% (RH)

2.3 REFERENCE DOCUMENT

The test is based on MIL-STD-883H Method 3015.8

2.4 TEST CONDITION

IO,VCC TO VSS(+)
IO,VCC TO VSS(-)
IO,VSS TO VCC(+)
IO,VSS TO VCC(-)
IO TO IO(+)
IO TO IO(-)

2.5 SUMMARY OF TEST

Test Model : HBM	**ESD Sensitivity Passed : ±2000V**		**MIL-STD Classification** **Class : 2**
Test condition	Sample Quantity	Passed Volts	**Class 0 : ＜ 250V.** **Class 1A : ≧ 250V , ＜500V** **Class 1B : ≧ 500V , ＜1000V** **Class 1C : ≧1000V , ＜2000V** **Class 2 : ≧2000V , ＜4000V** **Class 3A : ≧4000V , ＜8000V** **Class 3B : ≧8000V**
IO,VCC TO VSS(+)	3	+2000	
IO,VCC TO VSS(-)	3	-2000	
IO,VSS TO VCC(+)	3	+2000	
IO,VSS TO VCC(-)	3	-2000	
IO TO IO(+)	3	+2000	
IO TO IO(-)	3	-2000	

VSS: Pin4;

VCC: Pin8;

IO: Pin1-3, 5-7;

2.6 CONTENTS OF TEST

IO,VCC TO VSS(+)			
Tested Pin	Sample No. & Failed Volt (V)		
	#1-1	#1-2	#1-3
1	PASS	PASS	PASS
2	PASS	PASS	PASS
3	PASS	PASS	PASS
5	PASS	PASS	PASS
6	PASS	PASS	PASS
7	PASS	PASS	PASS
8	PASS	PASS	PASS

IO,VCC TO VSS(-)			
Tested Pin	Sample No. & Failed Volt (V)		
	#2-1	#2-2	#2-3
1	PASS	PASS	PASS
2	PASS	PASS	PASS
3	PASS	PASS	PASS
5	PASS	PASS	PASS
6	PASS	PASS	PASS
7	PASS	PASS	PASS
8	PASS	PASS	PASS

IO,VSS TO VCC(+)			
Tested Pin	Sample No. & Failed Volt (V)		
	#3-1	#3-2	#3-3
1	PASS	PASS	PASS
2	PASS	PASS	PASS
3	PASS	PASS	PASS
4	PASS	PASS	PASS
5	PASS	PASS	PASS
6	PASS	PASS	PASS
7	PASS	PASS	PASS

IO,VSS TO VCC(-)			
Tested Pin	Sample No. & Failed Volt (V)		
	#4-1	#4-2	#4-3
1	PASS	PASS	PASS
2	PASS	PASS	PASS
3	PASS	PASS	PASS
4	PASS	PASS	PASS
5	PASS	PASS	PASS
6	PASS	PASS	PASS
7	PASS	PASS	PASS

IO TO IO(+)			
Tested Pin	Sample No. & Failed Volt (V)		
	#5-1	#5-2	#5-3
1	PASS	PASS	PASS
2	PASS	PASS	PASS
3	PASS	PASS	PASS
5	PASS	PASS	PASS
6	PASS	PASS	PASS
7	PASS	PASS	PASS

IO TO IO(-)			
Tested Pin	Sample No. & Failed Volt (V)		
	#6-1	#6-2	#6-3
1	PASS	PASS	PASS
2	PASS	PASS	PASS
3	PASS	PASS	PASS
5	PASS	PASS	PASS
6	PASS	PASS	PASS
7	PASS	PASS	PASS